ΗΙΟΚΙ

IN-CIRCUIT TESTER FA1220 SHORT-OPEN TESTER FA1221

High-speed multifunction testing of populated boards

Compact modular in-circuit tester FA1220



FA1220

Multichannel high-speed short/open testing

Embeddable short/open tester FA1221

- od samelov actifilitient to film very early to redama ed) al exercicil faceling E 🗆 1024
- 🔲 Global-ready: CE Mark and KG Mark compliant
- essessong elyfilum enflmesnis af essessong griftest refio difw enflmod 🗆 cessessong elyfilum enflmes a and wolkkow elynis a and
- 🔲 ldeal for embedding in reduced-manpower or unmanned automated systems



FA1220/FA1221 shared features

High-speed, multichannel testing

Digital signal processing has been redesigned from Hioki's legacy 1220-50 series. Processing capacity has been increased 16% compared to legacy models.

Easy-to-use interface

Your testing line computer can be used to configure test conditions for, and control, both the FA1220 and FA1221. (Subject to limitations imposed by the recommended operating specifications.) The test tool can coexist with your existing computer applications, which can be used to control the FA1220/FA1221 control application.

In addition, the FA1220/FA1221 uses a general-purpose LAN connection, simplifying the wiring process inside your testing system.

I/O allocation function

When embedding the FA1220/FA1221 in an existing tester, an I/O interface is essential. Since you can assign the necessary signals to the connector pin numbers you specify using the FA1220/FA1221's I/O board (option), the system can be easily upgraded.

FA1220 features

More channels

The FA1220 provides more channels per unit of installation

space than Hioki's legacy models.

Legacy 1220-50: Up to 320 pins per rack

New FA1220: Up to 1,024 pins per rack

Since you can save space when using numerous channels (measurement pins), it's easier than ever before to embed the product in existing equipment.



Streamlining of testing processes

Since the FA1220 is the size of a mini-tower computer (200 [W] \times 323 [H] \times 298 [D] mm), it can be embedded in existing automated equipment, saving installation space and additional costs.

Ideal design for embedding in reduced-manpower or unmanned automated equipment

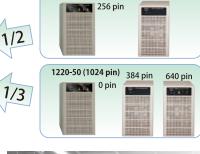
Electronic control units (ECUs) for electric vehicles (EVs) and motor drive circuits for industrial robots are often used in mission-critical devices where malfunctions are unacceptable. As a result, electronic circuit boards must deliver both high quality and high reliability.

Demand for the ability to quickly and accurately test large quantities of electronic circuit boards is increasing, and the production lines of the future will require smart factories, as evidenced by initiatives such as Society 5.0 (Japan) and Industry 4.0 (German). In this context, the compact, modular FA1220, which can be embedded in existing automated equipment to perform high-quality, high-reliability measurement, is ideal.









640 pin

1220-50 (896 pin)





Embed Electronic Circuit Board Component, Mounting Status, and Function Testing into Existing Equipment



Computer and peripherals not included in FA1220. A separate control computer is required in order to use the FA1220 on a standalone basis

- Functionality has been consolidated in a single, desktop tower that can be easily embedded in existing equipment
- Extensive function testing
- . Electrolytic capacitor and IC reverse insertion detection
- Macro-testing function to increase test efficiency
- Four-terminal low-resistance measurement for stable measurement of • low resistance

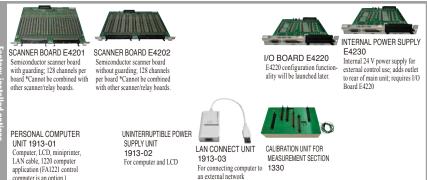
Model No. (Order Code) FA1220 (Main unit only)

Data from the legacy 1101 and 1102 cannot be converted for use by the 1220 (FA1220) because Hioki is unable to supply computers that can run the 1137 Support Software.
Data compatibility between the FA1220/FA1221 and legacy products (1220-00/-01/-02/-11/-50/-51/-52/-55): Although data created for legacy products can be used, such data is not fully compatible with the FA1220/ FA1221. It may be necessary to perform stray capacitance acquisition, wiring resistance acquisition, S/O data acquisition, IC data acquisition, and component test debugging. In particular, it may be necessary to reacquire stray capacitance in applications that involve measurement of minuscule capacitance values.

FA1220 Specifications

Number of test points	Max. 1024 pins (Can be added in blocks of 128 pins.) Standard : 0 pins (Scanner boards are sold as options.)		
Number of test steps	Round-robin short/open data : 1024 pins Component data : Max. 10000 steps Macro data : 1024 pins/1024 steps (regardless of number of pins) IC data : 500 steps (max. 1024 pins/step) Charge data : 40 sets Pin contact data : 1024 pins Group data : 255 groups		
Test parameters and measurement ranges	Round-robin short/open :	4Ω to $400 \text{ k}\Omega$ (Default: 40Ω)	
	Macro testing (impedance) :	1 Ω to 10 MΩ	
	Component tests :	Possible	
	IC reverse insertion detection :	Possible	
Component tests	Resistance :	$400\mu\Omega$ to $40M\Omega$	
	Impedance :	1Ω to $10 M\Omega$	
	Capacitor (capacitance) :	10 pF to 400 mF	
	Coil (inductance) :	1 µH to 1 H	
	Diode/transistor :	0 V to 25 V	
	Zener diode :	0 V to 25 V	
	Digital transistor :	0 V to 25 V	
	MOSFET on-resistance :	0Ω to 1000Ω	
	JFET drain current N ch :	0 A to 20 mA	
	JFET drain current P ch :	-20 mA to 0 mA	
	Photocoupler test :	0 V to 25 V	
	DC voltage :	0 V to 25 V	
	Open :	4Ω to $4 M\Omega$	
	Short :	$400~m\Omega$ to $400~k\Omega$	
	Discharge :	Possible	
	Capacitor reverse insertion detection :	Possible	

	DC constant voltage :	-200 m / 100 m / 400 mV / 10 V: 4 ranges	
	DC constant current :	200 nA to 20 mA, 11 ranges	
		160 Hz 0.1 Vrms, 1.6 kHz 0.1 Vrms, 0.2 Vrms to 2.0 Vrms / 0.1 V steps	
Test signals		16 kHz 0.1 Vrms, 160 kHz 0.1 Vrms,	
Ũ		0.2 Vrms to 2.0 Vrms / 0.1 V steps	
		0.2 to 0.5 Vrms / 0.1 V steps (ATG step testing)	
		0.2 to 2.0 Vrms / 0.1 V steps (testing between specified pins) Frequency: 1.6 kHz, 160 kHz	
		800 µV f.s. to 25 V f.s., 8 ranges	
Measurement unit		100 nA f.s. to 250 mA f.s., 9 ranges 10 μArms f.s. to 10 mA rms f.s., 4 ranges	
unit		Ammeter $10 \mu/100 \mu/1 m/10$ m Arms, 4 ranges	
0	Software used : Analog switch (Scanner board E4201, E4202)		
Scanner unit*2	Number of channels : 128 channels/board (2-/4-terminal switchable)		
		15 V/±0.5 V (Batch-configurable, Scanner Board E4201/E4202 only)	
Judgment range	-99.9% to +999.9% or		
	Round-robin short/op		
	Component :	From approx. 0.9 ms per step	
Measurement times	Macro :	From approx. 2.0 ms per step	
umes	IC test : Charge :	From approx. 1.0 ms per pin From approx. 3.0 ms per set	
	Pin contact test :	From approx. 1.0 ms per pin	
Guarding		Tom approx. To his per phi	
Guarding Self-test func-	Max. 5 points / step		
tion	Execution method: Separate (manual) / at startup / at automatic test Test items: AD function, DC function, AC function, scanner boards, fixture		
Statistics func- tionality	Defect rate tabulation and graph display by pin, test, group, and overall; com- ponent test histogram; operating time cumulative and subtotal displays		
Automatic data creation function	ATG function (automatic acquisition of reference data and automatic configuration of guarding points), reference value acquisition, wiring resistance cancellation, stray capacitance cancellation, group specification		
External I/O *2	Using I/O Board E4220*1 : 60 inputs, 56 outputs *1 Hioki plans to update the FA1220'FA1221 to provide functionality for configuring the I/O Board E4220. *2 Sold separately.		
	2 Sold Separately.		
	Location of use :	Indoors, Pollution Level 2, maximum elevation of 2000 m	
	Location of use : Op. temp. /humidity rang	e: Temperature: 23°C ±10°C, 75% RH or less (non-condensing)	
Operating envi-	Location of use : Op. temp. /humidity rang	ye: Temperature: 23°C ±10°C, 75% RH or less (non-condensing) ange: Temperature: 10°C to 43°C, 75% RH or less (non-condensing) Do not use in a setting where the product would be exposed to	
Operating envi- ronment	Location of use : Op. temp. /humidity rang Storage temp./humidity ra	e : Temperature: 23°C ±10°C, 75% RH or less (non-condensing) ange : Temperature: 10°C to 43°C, 75% RH or less (non-condensing)	
	Location of use : Op. temp. /humidity rang Storage temp./humidity ra Environment :	te: Temperature: 23°C ±10°C, 75% RH or less (non-condensing) ange: Temperature: 10°C to 43°C, 75% RH or less (non-condensing) Do not use in a setting where the product would be exposed to dust, vibration, corrosive gases, etc.	
	Location of use : Op. temp./humidity rang Storage temp./humidity ra Environment : Vibration : Standard compliance : External computer (sold s	 Temperature: 23°C±10°C, 75% RH or less (non-condensing) Temperature: 10°C to 43°C, 75% RH or less (non-condensing) Do not use in a setting where the product would be exposed to dust, vibration, corrosive gases, etc Avoid use in locations with excessive vibration. Safety EN 61010-1:2010, EMC: EN 61326-1:2013 Class A eparately) 	
	Location of use : Op. temp. /humidity rang Storage temp./humidity ra Environment : Vibration : Standard compliance : External computer (sold s System requirements: Op memory: 4 GB or more;	te: Temperature: 23°C ±10°C, 75% RH or less (non-condensing) ange: Temperature: 10°C to 43°C, 75% RH or less (non-condensing Do not use in a setting where the product would be exposed to dust, vibration, corrosive gases, etc Avoid use in locations with excessive vibration. Safety EN 61010-1:2010, EMC: EN 61326-1:2013 Class A	
ronment	Location of use : Op. temp. /humidity rang Storage temp./humidity ra Environment : Vibration : Standard compliance : External computer (sold s System requirements: Op memory: 4 GB or more; FA1220: Real-time operal Retry, retry with switched test results output (printer/fi stop; password protection;] switching (A/B data); point	te: Temperature: 23°C±10°C, 75% RH or less (non-condensing) ange: Temperature: 10°C to 43°C, 75% RH or less (non-condensing Do not use in a setting where the product would be exposed to dust, vibration, corrosive gases, etc Avoid use in locations with excessive vibration. Safety EN 61010-1:2010, EMC: EN 61326-1:2013 Class A reparately) erating system: Windows 10 64-bit Japanese or English version; hard disk: At least 20 GB of available space on install drive ting system, LAN for PC connectivity (10 / 100 ×1 port) polarity, or retest at defective contact; FAIL stop, test jump, test hold le}; FAIL map display; mask pin setting; surplus test; consecutive FAII oading/conversion of existing model data (105 or text data); test data	
Control unit	Location of use : Op. temp. /humidity rang Storage temp./humidity ra Environment : Vibration : Standard compliance : External computer (sold s System requirements: Op memory: 4 GB or more; FA1220: Real-time operar Retry, retry with switched test results output (printer/fi stop, password protection; switching (A/B data); point connectivity (option); pin se	te: Temperature: 23°C ±10°C, 75% RH or less (non-condensing) ange: Temperature: 10°C to 43°C, 75% RH or less (non-condensing) Do no tuse in a setting where the product would be exposed to dust, vibration, corrosive gases, etc Avoid use in locations with excessive vibration. Safety EN 61010-1:2010, EMC: EN 61326-1:2013 Class A erating system: Windows 10 64-bit Japanese or English version; hard disk: At least 20 GB of available space on install drive ting system, LAN for PC connectivity (10 / 100 ×1 port) polarity, or retest at defective contact; FAIL stop; test jump; test hold lej; FAIL map display; mask pin setting; surplus test; consecutive FAIL loading/conversion of existing model data (1105 or text data); test data; viewer, prevention of fixture raising at FAIL; barcode support; networl arch with audio guidance; overall PASS/FAIL stamp (option)	
Control unit Functionality	Location of use : Op. temp. /humidity rang Storage temp./humidity ra Environment : Vibration : Standard compliance : External computer (sold s System requirements: Op memory: 4 GB or more; FA1220: Real-time operal Retry, retry with switched test results output (printer/fi stop; password protection; switching (A/B data); point connectivity (option); pin se 100 to 240 V AC (±10°; 1024 pins of scanner but	 temperature: 23°C ±10°C, 75% RH or less (non-condensing) ange : Temperature: 10°C to 43°C, 75% RH or less (non-condensing) Do no tuse in a setting where the product would be exposed to dust, vibration, corrosive gases, etc Avoid use in locations with excessive vibration. Safety EN 61010-1:2010, EMC: EN 61326-1:2013 Class A reparately) reating system: Windows 10 64-bit Japanese or English version; hard disk: At least 20 GB of available space on install drive ting system, LAN for PC connectivity (10 / 100 ×1 port) polarity, or retest at defective contact; FAIL stop; test jump; test hold lie); FAIL map display; mask pin setting; surplus test; consecutive FAIL loading/conversion of existing model data (1105 or text data); test dat viewer, prevention of fixture raising at FAIL; barcode support; networf arch with audio guidance; overall PASS/FAIL stamp (option) %), single-phase, 50 Hz / 60 Hz, max. 260 W (with full 	





Factory-installed options

computer is an option.)

FA1221 features

Specifically designed for resistance testing

Designed specifically for short/open and resistance testing of flexible printed circuit boards, harnesses, connectors, semiconductor probers, welds, distribution panel wiring, and other targets to deliver exceptional cost performance.

For reliability testing of electronic components, cables, and connectors

The FA1221 enables flexible, computer-based operation. It provides functionality that will be useful in testing applications, for example measurement of long-term trends in resistance values. (Cable bend durability testing, semiconductor solder overload degradation testing, relay contact durability testing, etc.)

For resistance testing of welds in fuel cell batteries

Fuel cell batteries consist of multiple cells. Since high tab weld resistance in cells leads to battery degradation, weld resistance testing is a key quality control metric, creating demand for systems that can perform efficient, highly reliable testing across large numbers of channels.



Battery pack (Consisting of multiple modules)

Multichannel Short/Open Tester that can be Embedded in Your Test Equipment

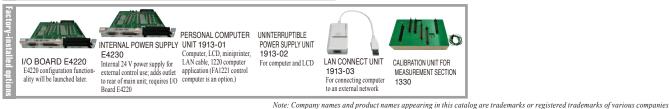


- Functionality has been consolidated in a single, desktop tower that can be easily embedded in existing equipment
- Specifically designed for short/open testing
- Four-terminal low-resistance measurement for stable measurement of low resistance

Model No. (Order Code) FA1221 (Main unit only)



Number of test points	128 pins (during 4-terminal	measurement, up to 32 sets)	
Number of test steps	Round-robin short/open : 128 pins Component data : Max. 10000 steps Charge data : 40 sets Pin contact data : 128 pins Group data : 255 groups		
Test parameters and measurement ranges	Round-robin short/open : Component tests :	4Ω to 400 k Ω (Default: 40 Ω) Possible	
Component tests	Resistance : Open : Short :	$\begin{array}{l} 400 \; \mu\Omega \; to \; 40 \; M\Omega \\ 4 \; \Omega \; to \; 4 \; M\Omega \\ 400 \; m\Omega \; to \; 40 \; \Omega \end{array}$	
Test signals	DC constant voltage : DC constant current :	100 m / 400 mV : 2 ranges 2 m / 20 mA, 2 ranges	
Measurement unit	DC ammeter : Ammeter $80 \mu / 800 \mu / 4 m / 40 m Arms$, 4 ranges DC ammeter : $250 n / 2.5 \mu / 25 \mu / 250 \mu / 2.5 m / 25 m A f.s.$, 6 ranges		
Scanner unit	Analog software : 128 channels/board (2-/4-terminal switchable, no guarding)		
Judgment range	-99.9% to +999.9% or absolute value		
Measurement times	Round-robin short/open : From approx. 0.8 ms per pin Component : From approx. 0.9 ms per step		
Statistics func- tionality	Defect rate tabulation and graph display test, group, and overall; component test histogram; operating time cumulative and subtotal displays		
External I/O *2	Using I/O Board E4220*1: 60 inputs, 56 outputs *1 Hioki plans to update the FA1220/FA1221 to provide functionality for configuring the I/O Board E4220. *2 Sold separately.		
Power supply	100 to 240 V AC (±10%), single-phase, 50 Hz / 60 Hz, max. 130 W		
Dimensions and mass	200 mm (7.87 in) W × 323 mm (12.72 in) H × 298 mm (11.73 in) D, 10 kg (352.7 oz)		
Accessories	Instruction manual ×1, Test leads ×1, Power cord ×1, Metal fittings ×1, Installation CD ×1		



DISTRIBUTED BY

HIOKI E.E. CORPORATION

HEADQUARTERS

81 Koizumi Ueda, Nagano 386-1192 Japan https://www.hioki.com/



regional contact information

All information correct as of Dec. 12, 2019. All specifications are subject to change without notice.

FA1220 1221E1-9ZM Printed in Japan